

APJ ABDULKALAM TECHNOLOGICAL UNIVERSITY
08 PALAKKAD CLUSTER

Q. P. Code : VLS0819322-I

(Pages: 2)

Name:

Reg. No:.....

SECOND SEMESTER M.TECH. DEGREE EXAMINATION APRIL 2019

Branch: Electronics And Communication Engineering

Specialization: VLSI Design

08 EC 6322 CAD OF VLSI CIRCUITS

(VLSI DESIGN)

Time:3 hours

Max. marks: 60

Answer all six questions.

Modules 1 to 6: Part 'a' of each question is compulsory and answer either part 'b' or part 'c' of each question.

Q.no.	Module 1	Marks
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1.a Define the concepts of Place and Route.		(3)
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b Explain in detail about Layout editor tools.		(6)
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OR

c Discuss on the various types of Back End tools.		(6)
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Q.no.	Module 2	Marks
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2.a Give a brief description on VLSI Methodologies.		(3)
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b Illustrate the VLSI Physical design Automation.		(6)
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OR

c Explain about Design and Fabrication of VLSI decives.		(6)
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Q.no.	Module 3	Marks
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3.a Briefly explain about Verilog Basis		(3)
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b Explain about:		(6)
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i) List of ports

ii) Port declaration

iii) Port connection rules

OR

c Investigate the Basic language concepts in VLSI Design. (6)

Q.no.	Module 4	Marks
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4.a Evaluate the dataflow modeling in NAND GATE.		(3)
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b Outline the importance of Modeling system using Verilog HDL.		(6)
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OR

c Illustrate the dataflow modeling in 4:1 Multiplexer.		(6)
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Q.no.	Module 5	Marks
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5.a Explain about Placement.		(4)
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b Discuss in detail about routing algorithm.		(8)
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OR

c Describe the importance of Post- layout Simulation with necessary examples.		(8)
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Module 6

6.a List out the steps for PODEM algorithm.		(4)
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b Write in detail about Automatic Test Pattern Generation.		(8)
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OR

c Illustrate Scan- based testing of sequential circuits with necessary block diagrams.		(8)
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